

Notice of References Cited	Application/Control No. 10/664,671	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Shean C. Wu	Art Unit 1756	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	T	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05-112778	05-1993	Japan	---	---
	O					
	P					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English abstract for JP 05-112778.
	V	CAPLUS 1994: 285205
	W	CAPLUS 1967: 489834
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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